

LECTURE

Flash

(NAND) Flash

(refs 7, 16, 17)

→ VSCD paper
(micro 2009)
→ DFTL
(ASPLoS 109)

data: charge trapped in a gate
each gate can store 1/more bits
(SLC) (MLC)

internally;



bank:
divided into blocks (size 128k → 256k)

~~block~~
divided into pages (size ~2k → 8k)
(data + OOB)

three primary operations:

erase (block) → sets all bits to 1

program (page) → can change 1's → 0's
(same)

⇒ must erase block before
programming page w/in block

read (page) → read whole page (in parallel)

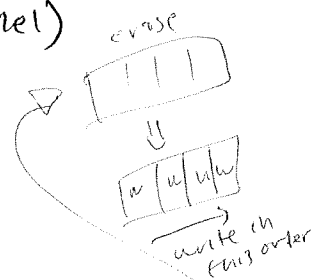
performance: (per page)

read latency ~ 10 μ s (10-50)

prog latency ~ 200 → 500 μ s

erase ~ 2 ms

~ 200 MB/s



reliability:

primary problem: wearout

erase/program cycle → trapped charge →

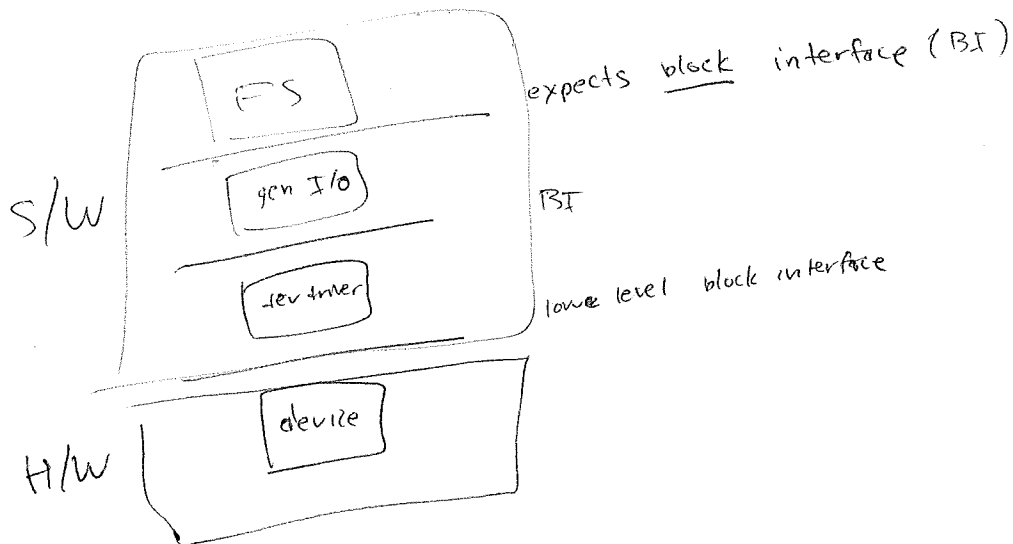
for each block: 10k P/E cycles (MLC)
100k P/E cycles (SLC)

also, program disturb ⇒ when prog one page, neighbor may be affected
⇒ program in order (once written, only one strong disturb will happen)

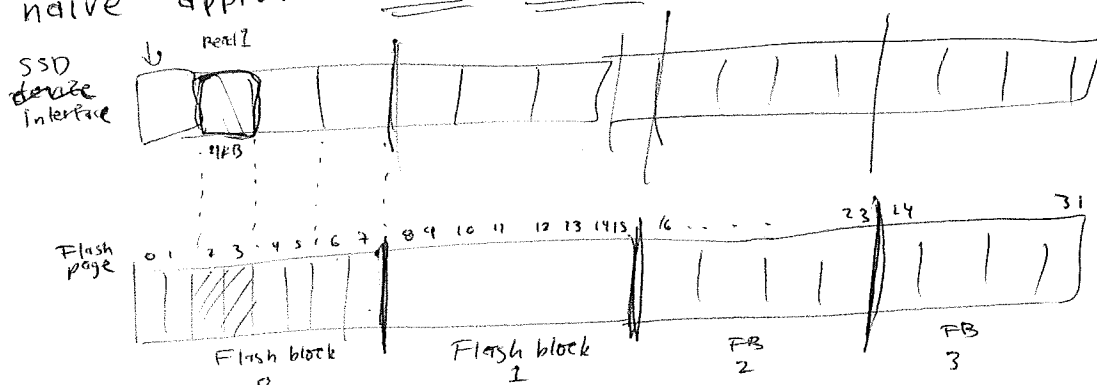
no moving parts!
rare catastrophic failure
→ relatively high bit-error rates
(disturb)
can't tell difference between 1/0

ugly
partial-page
prog
→ data retention
@ high temp

how to use in system?



naive approach: direct mapping



read 1 \Rightarrow read (2,3) \Rightarrow works!

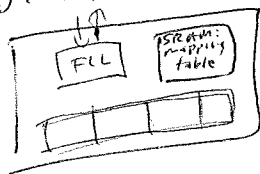
write 1 \Rightarrow erase (0), program (2,3)

bad why? \Rightarrow performance (each erase ~ 2 ms)

\Rightarrow reliability (wear out!)
(prog. disturb)

more sophisticated/real: flash translation layer (FTL)

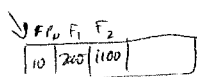
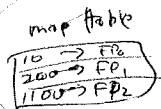
SSD: looks like disk



takes read/write blocks

e, p, r of blocks/page

write 10
write 200
write 1100



(simple page mapping)

page-mapped

Implications of FTL:

→ can erase blocks in background

→ fill in log-structured style \Rightarrow helps w/ wear leveling (reliability)

performance \Rightarrow good!

perf

\Rightarrow generates garbage

→ device must find old blocks, clean, make available again
→ device must also make sure to wear level blocks

reliability

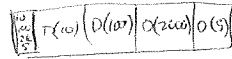
device tracks:

live/dead: how?

erasure count / block: how?

(must periodically clean block for wear too!)

cost area



examine block
check map table

Problem: mapping table is too big! (costly, energy)

compute size: 260 GB device w/ 2K pages

100 m entries \neq 4 MB \Rightarrow 400 MB in device!

solutions:

zoning (low-end) \Rightarrow

map table per zone in/out mem
(keep most tables in flash)

larger mappings \Rightarrow
(not used)

makes table smaller:
@ what cost?

[program of small page \Rightarrow read block, write block (+ new page)
(RMW cycle) \Rightarrow costly

common: hybrid (both page-level + block-level)

most of SSD: Data blocks (block mapped) $\approx 95\%$

small, active write area: Log blocks (page mapped) $< 5\%$

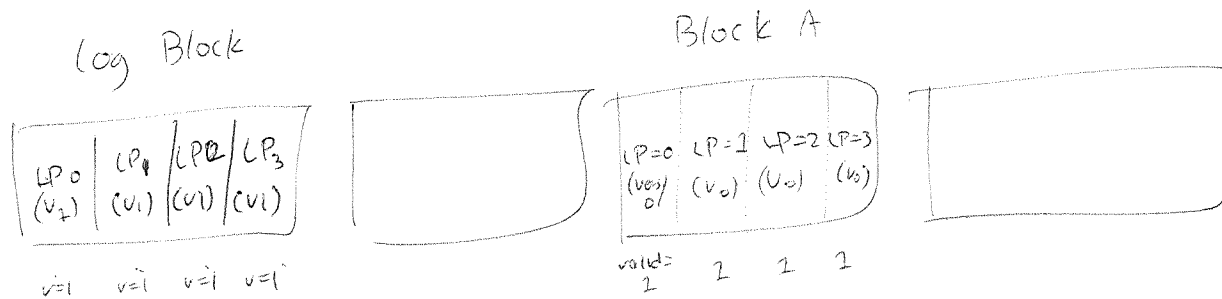
tricky part: GC

switch merge: after seq write \Rightarrow log,
switch log + dest block

Block size = 4

Page Num
0 1 2 3 / 4 5 6 7
BN=0 BN=2
BN = PN / $\frac{\text{block size}}{\text{page size}}$
Boff = PN % $\frac{\text{block size}}{\text{page size}}$

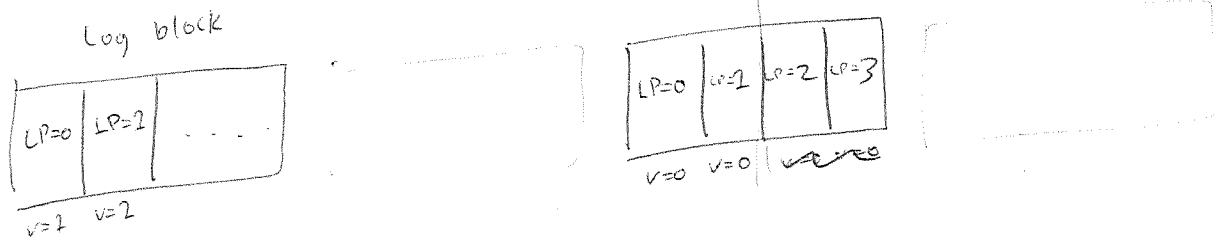
switch merge



make A \Rightarrow log block
(erase it)

make L \Rightarrow data block
(update mapping)

partial merge



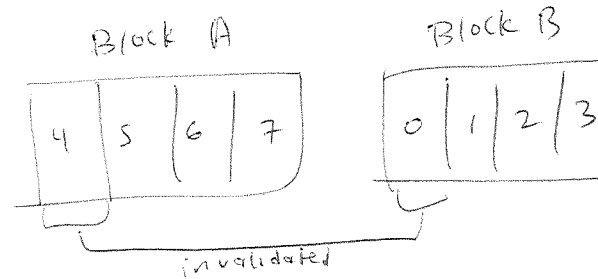
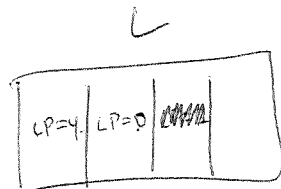
rest 2,3 from A

write (prog) to L

call L \rightarrow A

call A \rightarrow L

full merge



\Rightarrow find new erased C

\Rightarrow merge 0(L) + (1,2,3)B

\Rightarrow C

(erase B) \Rightarrow L

\Rightarrow merge (5,6,7)_A \Rightarrow L
(erase A)

end result:

SSDs

seq r/w \Rightarrow good (100s of MB/s)

rand read \Rightarrow good (nearly seq)

rand write \Rightarrow bad (lots of GC + merging)

FS implications?